

**Search Notes****Application/Control No.**

10/825,100

**Examiner**

Binh X. Tran

**Applicant(s)/Patent under Reexamination**

KONDO ET AL.

**Art Unit**

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	693	6/2/2006	BT
438	695	6/2/2006	BT
438	697	6/2/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search inventor's name and keywords using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/2/2006	BT

**INTERFERENCE SEARCHED**

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